

2623

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 09/697,025

Confirmation No.: 3437

First Named Inventor: Mehrdad Nikoonahad

Filing Date: October 26, 2000

Group Art Unit: 2623

Examiner: Unknown

Atty. Docket No.: TNCR.183US0

Title: OVERLAY ERROR DETECTION

Assignee: KLA-TENCOR CORPORATION

San Francisco, California
March 31st, 2003

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

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Technology Center 2600

**SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, Applicants call the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

Copies of the documents listed on the accompanying Form PTO-1449 are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required.

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on March 31, 2003.

Valerie Olsen

Valerie Olsen

3/31/03

Date of Signature

Respectfully submitted,



James S. Hsue

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Attorney for Applicant(s)

U.S. Department of Commerce, Patent and Trademark Office		Atty Docket No.	Application No.
		TNCR.183US0	09/697,025
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		Applicant(s)	Confirmation No.
		Mehrdad Nikoonahad, et al.	3437
		Filing Date	Group
		October 26, 2000	2623

OCT 8 2003

PATENT & TRADEMARK OFFICE

U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,871,955	10/03/89	Berger	318	640	
	AB	5,495,336	02/27/96	Nose et al.	356	375	
	AD						
	AE						
	AF						
	AG						RECEIVED
	AI						APR 10 2003
	AJ						
	AD						Technology Center 2600
	AE						
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	AK						
	AD						
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	AG						
	AH						
	AI						

Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	R. Pforr, et al., "In-Process Image Detecting Technique For Determination Of Overlay, And Image Quality For ASM-L Wafer Stepper", SPIE Vol. 1674 Optical/Laser Microlithography V (1992) pp. 594-608		
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Examiner Date Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.